F-26

## **NJ72 Process**

# **Silicon Junction Field-Effect Transistor**

## VHF/UHF Amplifier

### Absolute maximum ratings at TA = 25°C

Gate Current, Ig 10 mA Operating Junction Temperature, Tj  $+150^{\circ}$ C Storage Temperature, Ts  $-65^{\circ}$ C to  $+175^{\circ}$ C

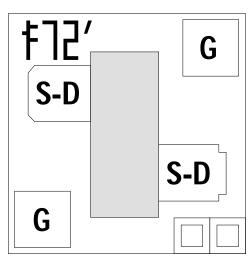
#### Devices in this Databook based on the NJ72 Process.

#### **Datasheet**

IFN5564, IFN5565 IFN5566 J308, J309 J308, J309 J310

### **Datasheet**

U308, U309 U430, U431 VCR2N



Die Size = 0.020" X 0.020" All Bond Pads = 0.004" Sq. Substrate is also Gate.

At 25°C free air temperature:			NJ72 Process						
Static Electrical Characteristics			Тур	Max	Unit	Test Conditions			
Gate Source Breakdown Voltage	V <sub>(BR)GSS</sub>	- 25	- 40		V	$I_G = -1 \mu A$ , $V_{DS} = \emptyset V$			
Reverse Gate Leakage Current	I <sub>GSS</sub>		- 10	- 100	pА	$V_{GS} = -15 V$ , $V_{DS} = \emptyset V$			
Drain Saturation Current (Pulsed)	I <sub>DSS</sub>	5		90	mA	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = Ø V			
Gate Source Cutoff Voltage	V <sub>GS(OFF)</sub>	- 1		- 5.5	V	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 1 nA			

### **Dynamic Electrical Characteristics**

Forward Transconductance	9 <sub>fs</sub>	2	22	mS	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = Ø V	f = 1 kHz
Drain Source ON Resistance	r <sub>ds(on)</sub>	4	40	Ω	$I_D = 1 \text{ mA}, V_{GS} = \emptyset V$	f = 1 kHz
Input Capacitance	C <sub>iss</sub>	6	5.5	pF	$V_{DS} = \emptyset V$ , $V_{GS} = -10 V$	f = 1 MHz
Feedback Capacitance	C <sub>rss</sub>	2	2.5	pF	$V_{DS} = \emptyset V$ , $V_{GS} = -10 V$	f = 1 MHz

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